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The diagram illustrates a system architecture with several interconnected components:

- Input/Output Devices:** Includes a keyboard (**p1**) and a mouse (**p2**).
- Storage and Data Management:** Features a stack of disks or tapes labeled **10**, and a central processing unit or controller labeled **30**.
- Processing Units:** Multiple units labeled **12** are shown, some connected via buses or networks.
- Network and Communication:** A circular network topology is depicted with nodes labeled **ST1**, **ST2**, **ST3**, **ST4**, **ST5**, and **ST6**. Arrows indicate data flow between these nodes.
- Data Flow and Control:** Various arrows and labels like **Sn1**, **Sp1**, **Sp2**, **Sp3**, **Sp4**, **96**, **97**, **88**, **51**, **52**, and **131** represent specific data paths, control signals, or storage elements within the system.

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ABSTRACT

An object is to provide an inspection sample making apparatus (30) that can simplify work for making an inspection sample (12) and can ensure inspection for seal condition. The inspection sample making apparatus (30) includes a preliminary-inspection-sample-making device (20) for peeling a predetermined fusion-bonded piece of a packaging container (10) off a wall of the packaging container (10) so as to make a preliminary inspection sample (20); and a cutting device for cutting the preliminary inspection sample (52) along a predetermined cutting line so as to make an inspection sample (12). Since the preliminary-inspection-sample-making device (20) peels a predetermined fusion-bonded piece of the packaging container (10) off a wall of the packaging container (10) to thereby make the preliminary inspection sample (52), and the cutting device cuts the preliminary inspection sample (52) along a predetermined cutting line to thereby make the inspection sample (12), an operator does not need to manually make the inspection sample (12). Therefore, not only is work for making the inspection sample (12) simplified, but also cutting at a wrong position is avoided. As a result, a seal condition inspection apparatus (31) can reliably inspect seal condition.